

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: OCHIAI, et al.

Serial No.: Not yet assigned

Filed: June 24, 2003

For: ELECTRON MICROSCOPE INCLUDING APPARATUS OF X-RAY
ANALYSIS AND METHOD OF ANALYZING SPECIMENS USING
SAME

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Assistant Commissioner for Patents
Washington, D.C. 20231

June 24, 2003

Sir:

In the matter of the above-identified application, applicants are submitting herewith a copy of a communication from a foreign patent office in a counterpart foreign application and copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.

Although some of the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by the discussion of the documents in the specification, for example, on pages three (3) and four (4).

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus Deposit Account No. 01-2135 (Case: 501.42867X00), and please credit any excess fees to such deposit account.

Respectfully submitted,

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Attachments

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 501.42867X00	SERIAL NO.
		INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	
		APPLICANT OCHIAI, et al. FILING DATE: June 24, 2003 GROUP	

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Abstract	
						Yes	No
	AM 63-108253	05/13/1988	JP	G01N	23/225	X	
	AN 8-148111	06/07/1996	JP	H01J	37/244	X	
	AO 2000-321225	11/24/2000	JP	G01N	23/225	X	
	AP 2001-68518	03/16/2001	JP	H01L	21/66	X	
	AQ						
	AR						
	AS						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	AU	
	AV	
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Examiner	Date Considered	